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Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	533MHz
Co-Processors/DSP	Security; SEC
RAM Controllers	DDR
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	672-LBGA
Supplier Device Package	672-LBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8347evvajdb

2.1.2 Power Supply Voltage Specification

Table 2 provides the recommended operating conditions for the MPC8347EA. Note that the values in Table 2 are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Parameter	Symbol	Recommended Value	Unit	Notes
Core supply voltage for 667-MHz core frequency	V_{DD}	$1.3 \text{ V} \pm 60 \text{ mV}$	V	1
Core supply voltage	V_{DD}	$1.2 \text{ V} \pm 60 \text{ mV}$	V	1
PLL supply voltage for 667-MHz core frequency	AV_{DD}	$1.3 \text{ V} \pm 60 \text{ mV}$	V	1
PLL supply voltage	AV_{DD}	$1.2 \text{ V} \pm 60 \text{ mV}$	V	1
DDR and DDR2 DRAM I/O voltage	GV_{DD}	$2.5 \text{ V} \pm 125 \text{ mV}$ $1.8 \text{ V} \pm 90 \text{ mV}$	V	—
Three-speed Ethernet I/O supply voltage	LV_{DD1}	$3.3 \text{ V} \pm 330 \text{ mV}$ $2.5 \text{ V} \pm 125 \text{ mV}$	V	—
Three-speed Ethernet I/O supply voltage	LV_{DD2}	$3.3 \text{ V} \pm 330 \text{ mV}$ $2.5 \text{ V} \pm 125 \text{ mV}$	V	—
PCI, local bus, DUART, system control and power management, I ² C, and JTAG I/O voltage	OV_{DD}	$3.3 \text{ V} \pm 330 \text{ mV}$	V	—

Note:

¹ GV_{DD} , LV_{DD} , OV_{DD} , AV_{DD} , and V_{DD} must track each other and must vary in the same direction—either in the positive or negative direction.

Figure 2 shows the undershoot and overshoot voltages at the interfaces of the MPC8347EA.

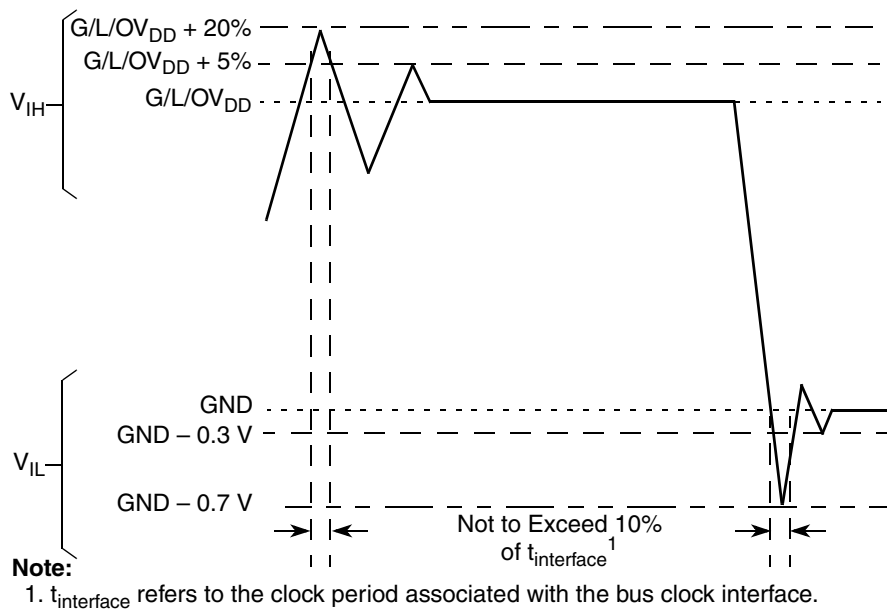


Figure 2. Overshoot/Undershoot Voltage for $GV_{DD}/OV_{DD}/LV_{DD}$

Table 5 shows the estimated typical I/O power dissipation for MPC8347EA.

Table 5. MPC8347EA Typical I/O Power Dissipation

Interface	Parameter	DDR2 GV _{DD} (1.8 V)	DDR1 GV _{DD} (2.5 V)	OV _{DD} (3.3 V)	LV _{DD} (3.3 V)	LV _{DD} (2.5 V)	Unit	Comments
DDR I/O 65% utilization 2.5 V Rs = 20 Ω Rt = 50 Ω 2 pair of clocks	200 MHz, 32 bits	0.31	0.42	—	—	—	W	—
	200 MHz, 64 bits	0.42	0.55	—	—	—	W	—
	266 MHz, 32 bits	0.35	0.5	—	—	—	W	—
	266 MHz, 64 bits	0.47	0.66	—	—	—	W	—
	300 MHz, ¹ 32 bits	0.37	0.54	—	—	—	W	—
	300 MHz, ¹ 64 bits	0.50	0.7	—	—	—	W	—
	333 MHz, ¹ 32 bits	0.39	0.58	—	—	—	W	—
	333 MHz, ¹ 64 bits	0.53	0.76	—	—	—	W	—
	400 MHz, ¹ 32 bits	0.44	—	—	—	—		—
	400 MHz, ¹ 64 bits	0.59	—	—	—	—		—
PCI I/O load = 30 pF	33 MHz, 32 bits	—	—	0.04	—	—	W	—
	66 MHz, 32 bits	—	—	0.07	—	—	W	—
Local bus I/O load = 25 pF	167 MHz, 32 bits	—	—	0.34	—	—	W	—
	133 MHz, 32 bits	—	—	0.27	—	—	W	—
	83 MHz, 32 bits	—	—	0.17	—	—	W	—
	66 MHz, 32 bits	—	—	0.14	—	—	W	—
	50 MHz, 32 bits	—	—	0.11	—	—	W	—
TSEC I/O load = 25 pF	MII	—	—	—	0.01	—	W	Multiply by number of interfaces used.
	GMII or TBI	—	—	—	0.06	—	W	
	RGMII or RTBI	—	—	—	—	0.04	W	
USB	12 MHz	—	—	0.01	—	—	W	Multiply by 2 if using 2 ports.
	480 MHz	—	—	0.2	—	—	W	
Other I/O		—	—	0.01	—	—	W	—

¹ TBGA package only.

Table 9. RESET Pins DC Electrical Characteristics¹ (continued)

Parameter	Symbol	Condition	Min	Max	Unit
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V

Notes:

1. This table applies for pins $\overline{\text{PORESET}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$, and $\overline{\text{QUIESCE}}$.
2. $\overline{\text{HRESET}}$ and $\overline{\text{SRESET}}$ are open drain pins, thus V_{OH} is not relevant for those pins.

5.2 RESET AC Electrical Characteristics

Table 10 provides the reset initialization AC timing specifications of the MPC8347EA.

Table 10. RESET Initialization Timing Specifications

Parameter	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$ or $\overline{\text{SRESET}}$ (input) to activate reset flow	32	—	$t_{\text{PCI_SYNC_IN}}$	1
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to CLKIN when the MPC8347EA is in PCI host mode	32	—	t_{CLKIN}	2
Required assertion time of $\overline{\text{PORESET}}$ with stable clock applied to PCI_SYNC_IN when the MPC8347EA is in PCI agent mode	32	—	$t_{\text{PCI_SYNC_IN}}$	1
$\overline{\text{HRESET}}/\overline{\text{SRESET}}$ assertion (output)	512	—	$t_{\text{PCI_SYNC_IN}}$	1
$\overline{\text{HRESET}}$ negation to $\overline{\text{SRESET}}$ negation (output)	16	—	$t_{\text{PCI_SYNC_IN}}$	1
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of $\overline{\text{PORESET}}$ when the MPC8347EA is in PCI host mode	4	—	t_{CLKIN}	2
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV) with respect to negation of $\overline{\text{PORESET}}$ when the MPC8347EA is in PCI agent mode	4	—	$t_{\text{PCI_SYNC_IN}}$	1
Input hold time for POR configuration signals with respect to negation of $\overline{\text{HRESET}}$	0	—	ns	—
Time for the MPC8347EA to turn off POR configuration signals with respect to the assertion of $\overline{\text{HRESET}}$	—	4	ns	3
Time for the MPC8347EA to turn on POR configuration signals with respect to the negation of $\overline{\text{HRESET}}$	1	—	$t_{\text{PCI_SYNC_IN}}$	1, 3

Notes:

1. $t_{\text{PCI_SYNC_IN}}$ is the clock period of the input clock applied to PCI_SYNC_IN. In PCI host mode, the primary clock is applied to the CLKIN input, and PCI_SYNC_IN period depends on the value of CFG_CLKIN_DIV. See the *MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual*.
2. t_{CLKIN} is the clock period of the input clock applied to CLKIN. It is valid only in PCI host mode. See the *MPC8349EA PowerQUICC II Pro Integrated Host Processor Family Reference Manual*.
3. POR configuration signals consist of CFG_RESET_SOURCE[0:2] and CFG_CLKIN_DIV.

Table 12. DDR2 SDRAM DC Electrical Characteristics for $GV_{DD}(\text{typ}) = 1.8 \text{ V}$ (continued)

Output low current ($V_{OUT} = 0.280 \text{ V}$)	I_{OL}	13.4	—	mA	—
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Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. MV_{REF} is expected to equal $0.5 \times GV_{DD}$, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} cannot exceed $\pm 2\%$ of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to equal MV_{REF} . This rail should track variations in the DC level of MV_{REF} .
4. Output leakage is measured with all outputs disabled, $0 \text{ V} \leq V_{OUT} \leq GV_{DD}$.

Table 13 provides the DDR2 capacitance when $GV_{DD}(\text{typ}) = 1.8 \text{ V}$.

Table 13. DDR2 SDRAM Capacitance for $GV_{DD}(\text{typ}) = 1.8 \text{ V}$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS, \overline{DQS}	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS, \overline{DQS}	C_{DIO}	—	0.5	pF	1

Note:

1. This parameter is sampled. $GV_{DD} = 1.8 \text{ V} \pm 0.090 \text{ V}$, $f = 1 \text{ MHz}$, $T_A = 25^\circ\text{C}$, $V_{OUT} = GV_{DD}/2$, V_{OUT} (peak-to-peak) = 0.2 V.

Table 14 provides the recommended operating conditions for the DDR SDRAM component(s) when $GV_{DD}(\text{typ}) = 2.5 \text{ V}$.

Table 14. DDR SDRAM DC Electrical Characteristics for $GV_{DD}(\text{typ}) = 2.5 \text{ V}$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	2.375	2.625	V	1
I/O reference voltage	MV_{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF} + 0.18$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	−0.3	$MV_{REF} - 0.18$	V	—
Output leakage current	I_{OZ}	−9.9	−9.9	μA	4
Output high current ($V_{OUT} = 1.95 \text{ V}$)	I_{OH}	−15.2	—	mA	—
Output low current ($V_{OUT} = 0.35 \text{ V}$)	I_{OL}	15.2	—	mA	—

Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. MV_{REF} is expected to be equal to $0.5 \times GV_{DD}$, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed $\pm 2\%$ of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF} . This rail should track variations in the DC level of MV_{REF} .
4. Output leakage is measured with all outputs disabled, $0 \text{ V} \leq V_{OUT} \leq GV_{DD}$.

6.2.2 DDR and DDR2 SDRAM Output AC Timing Specifications

Table 20 shows the DDR and DDR2 output AC timing specifications.

Table 20. DDR and DDR2 SDRAM Output AC Timing Specifications

At recommended operating conditions with GV_{DD} of (1.8 or 2.5 V) \pm 5%.

Parameter	Symbol ¹	Min	Max	Unit	Notes
MCK[n] cycle time, (MCK[n]/ $\overline{MCK[n]}$ crossing) (PBGA package)	t_{MCK}	5	—	ns	2
MCK[n] cycle time, (MCK[n]/ $\overline{MCK[n]}$ crossing) (TBGA package)	t_{MCK}	7.5	—	ns	2
ADDR/CMD/MODT output setup with respect to MCK 400 MHz 333 MHz 266 MHz 200 MHz	t_{DDKHAS}	1.95 2.40 3.15 4.20	— — — —	ns	3
ADDR/CMD/MODT output hold with respect to MCK 400 MHz 333 MHz 266 MHz 200 MHz	t_{DDKHAX}	1.95 2.40 3.15 4.20	— — — —	ns	3
$\overline{MCS}(n)$ output setup with respect to MCK 400 MHz 333 MHz 266 MHz 200 MHz	t_{DDKHCS}	1.95 2.40 3.15 4.20	— — — —	ns	3
$\overline{MCS}(n)$ output hold with respect to MCK 400 MHz 333 MHz 266 MHz 200 MHz	t_{DDKHGX}	1.95 2.40 3.15 4.20	— — — —	ns	3
MCK to MDQS Skew	t_{DDKMHM}	−0.6	0.6	ns	4
MDQ/MECC/MDM output setup with respect to MDQS 400 MHz 333 MHz 266 MHz 200 MHz	t_{DDKHDS} , t_{DDKLDS}	700 775 1100 1200	— — — —	ps	5
MDQ/MECC/MDM output hold with respect to MDQS 400 MHz 333 MHz	t_{DDKHDX} , t_{DDKLDX}	700 900	— —	ps	5

Table 32. MII Management DC Electrical Characteristics Powered at 2.5 V (continued)

Parameter	Symbol	Conditions	Min	Max	Unit
Input high current	I_{IH}	$V_{IN}^1 = LV_{DD}$	—	10	μA
Input low current	I_{IL}	$V_{IN} = LV_{DD}$	–15	—	μA

Note:

1. The symbol V_{IN} , in this case, represents the LV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

Table 33. MII Management DC Electrical Characteristics Powered at 3.3 V

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage (3.3 V)	LV_{DD}	—		2.97	3.63	V
Output high voltage	V_{OH}	$I_{OH} = -1.0 \text{ mA}$	$LV_{DD} = \text{Min}$	2.10	$LV_{DD} + 0.3$	V
Output low voltage	V_{OL}	$I_{OL} = 1.0 \text{ mA}$	$LV_{DD} = \text{Min}$	GND	0.50	V
Input high voltage	V_{IH}	—		2.00	—	V
Input low voltage	V_{IL}	—		—	0.80	V
Input high current	I_{IH}	$LV_{DD} = \text{Max}$	$V_{IN}^1 = 2.1 \text{ V}$	—	40	μA
Input low current	I_{IL}	$LV_{DD} = \text{Max}$	$V_{IN} = 0.5 \text{ V}$	–600	—	μA

Note:

1. The symbol V_{IN} , in this case, represents the LV_{IN} symbol referenced in [Table 1](#) and [Table 2](#).

8.3.2 MII Management AC Electrical Specifications

[Table 34](#) provides the MII management AC timing specifications.

Table 34. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD} is 3.3 V \pm 10% or 2.5 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	—
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
MDC to MDIO delay	t_{MDKHDX}	10	—	70	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	—
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	—

Table 34. MII Management AC Timing Specifications (continued)

At recommended operating conditions with V_{DD} is 3.3 V \pm 10% or 2.5 V \pm 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
MDC fall time	t_{MDHF}	—	—	10	ns	—

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a csb_clk of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz).
3. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the delay is 70 ns and for a csb_clk of 333 MHz, the delay is 58 ns).

Figure 17 shows the MII management AC timing diagram.

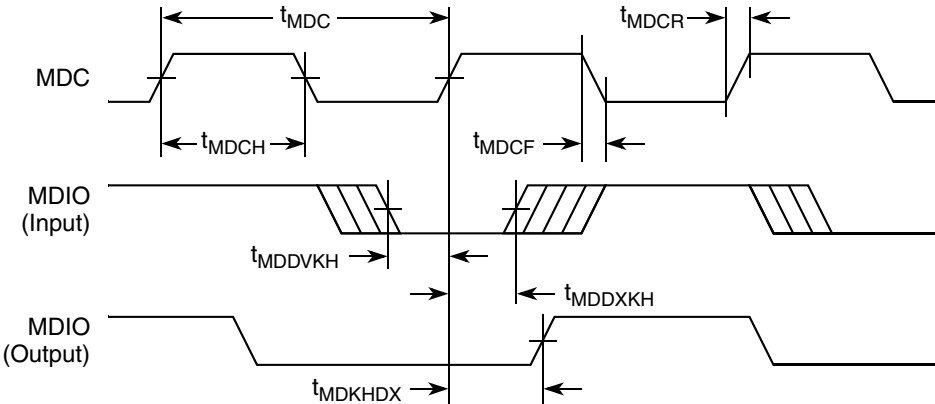


Figure 17. MII Management Interface Timing Diagram

Figure 21 through Figure 26 show the local bus signals.

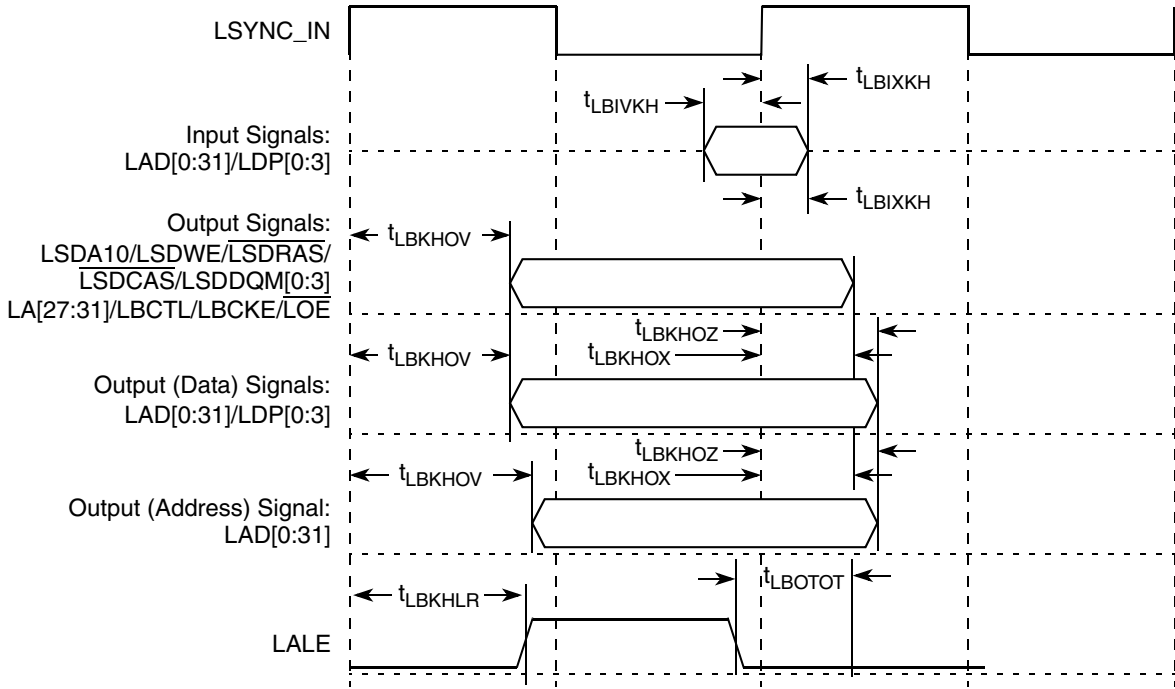


Figure 21. Local Bus Signals, Nonspecial Signals Only (DLL Enabled)

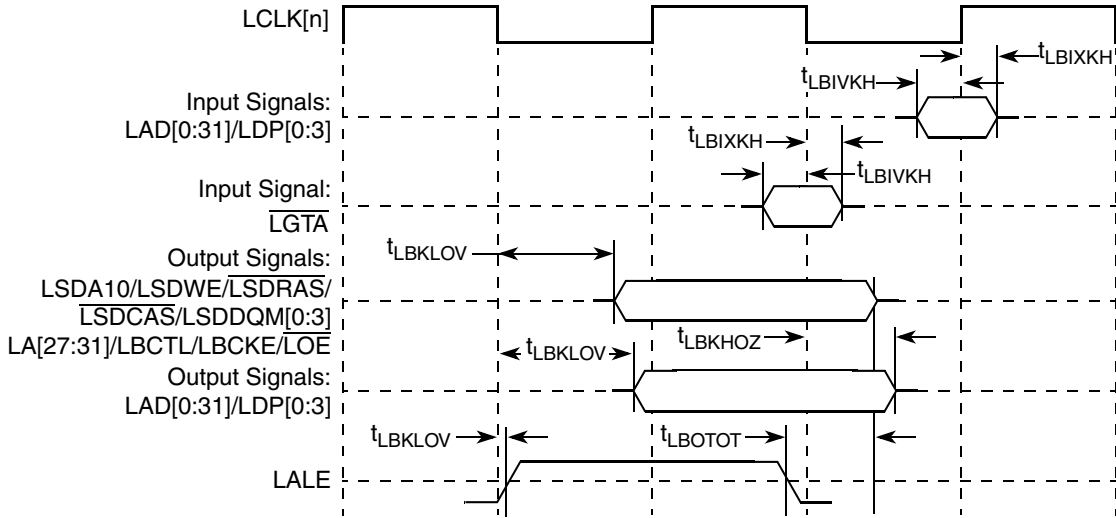


Figure 22. Local Bus Signals, Nonspecial Signals Only (DLL Bypass Mode)

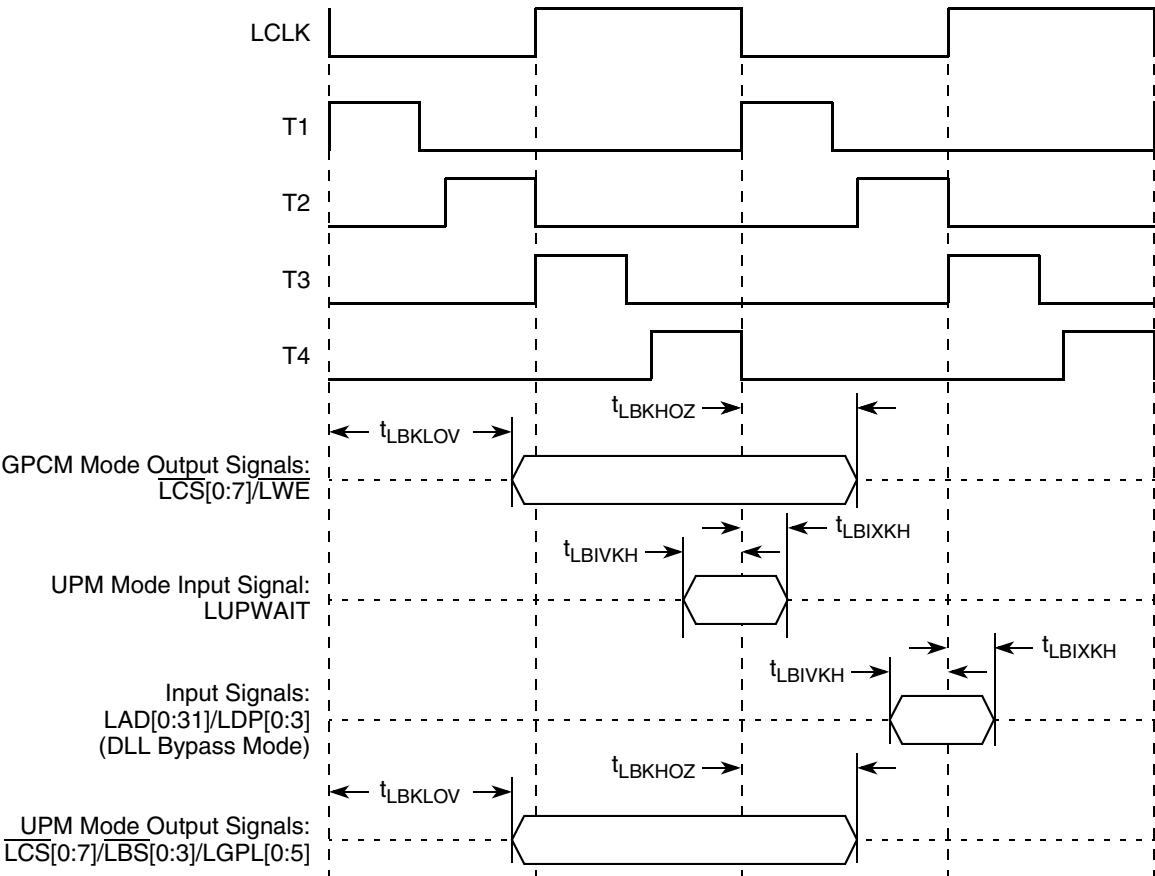


Figure 25. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Bypass Mode)

Figure 30 provides the boundary-scan timing diagram.

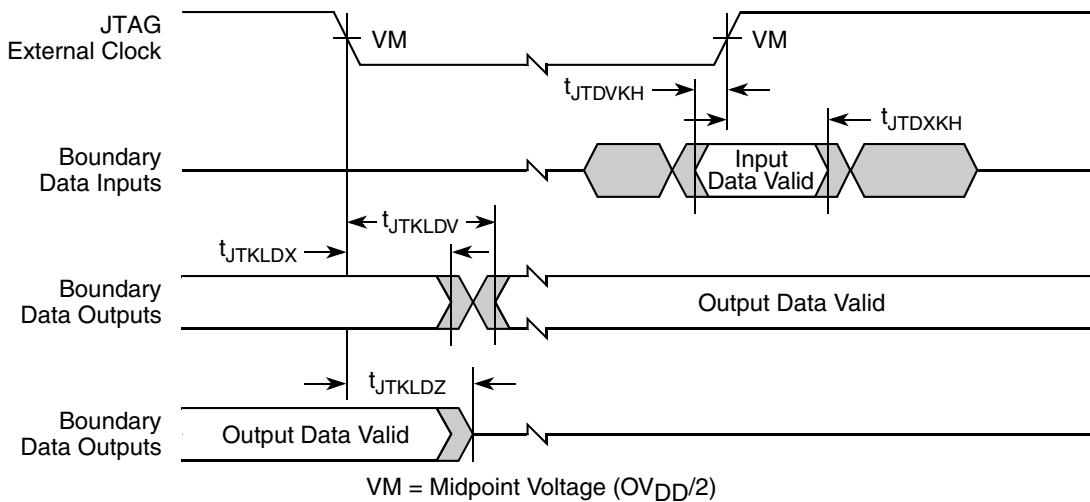


Figure 30. Boundary-Scan Timing Diagram

Figure 31 provides the test access port timing diagram.

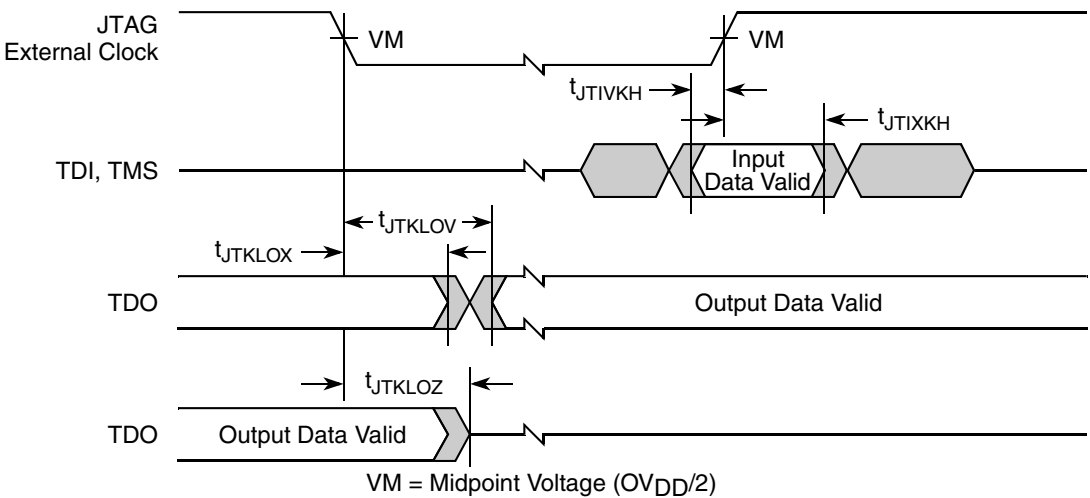
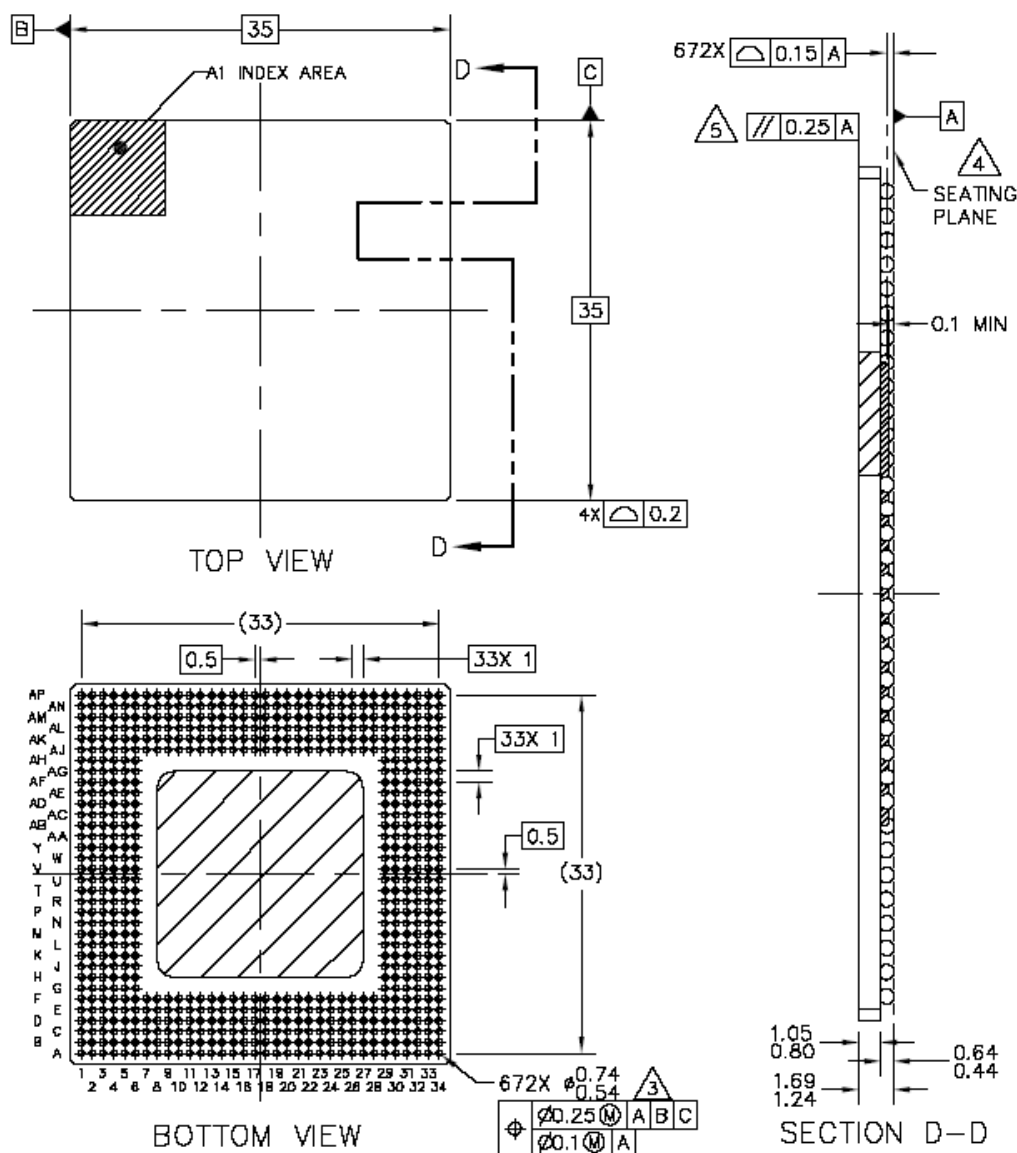


Figure 31. Test Access Port Timing Diagram

Pitch	1.00 mm
Module height (typical)	1.46 mm
Solder balls	62 Sn/36 Pb/2 Ag (ZU package) 96.5 Sn/3.5Ag (VV package)
Ball diameter (typical)	0.64 mm

18.2 Mechanical Dimensions for the MPC8347EA TBGA

Figure 40 shows the mechanical dimensions and bottom surface nomenclature for the MPC8347EA, 672-TBGA package.



Notes:

1. All dimensions are in millimeters.
2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement must exclude any effect of mark on top surface of package.

Figure 40. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC8347EA TBGA

18.5 Pinout Listings

Table 55 provides the pinout listing for the MPC8347EA, 672 TBGA package.

Table 55. MPC8347EA (TBGA) Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI				
PCI_INTA/IRQ_OUT	B34	O	OV _{DD}	2
PCI_RESET_OUT	C33	O	OV _{DD}	—
PCI_AD[31:0]	G30, G32, G34, H31, H32, H33, H34, J29, J32, J33, L30, K31, K33, K34, L33, L34, P34, R29, R30, R33, R34, T31, T32, T33, U31, U34, V31, V32, V33, V34, W33, W34	I/O	OV _{DD}	—
PCI_C/BE[3:0]	J30, M31, P33, T34	I/O	OV _{DD}	—
PCI_PAR	P32	I/O	OV _{DD}	—
PCI_FRAME	M32	I/O	OV _{DD}	5
PCI_TRDY	N29	I/O	OV _{DD}	5
PCI_IRDY	M34	I/O	OV _{DD}	5
PCI_STOP	N31	I/O	OV _{DD}	5
PCI_DEVSEL	N30	I/O	OV _{DD}	5
PCI_IDSEL	J31	I	OV _{DD}	—
PCI_SERR	N34	I/O	OV _{DD}	5
PCI_PERR	N33	I/O	OV _{DD}	5
PCI_REQ[0]	D32	I/O	OV _{DD}	—
PCI_REQ[1]/CPCI1_HS_ES	D34	I	OV _{DD}	—
PCI_REQ[2:4]	E34, F32, G29	I	OV _{DD}	—
PCI_GNT0	C34	I/O	OV _{DD}	—
PCI_GNT1/CPCI1_HS_LED	D33	O	OV _{DD}	—
PCI_GNT2/CPCI1_HS_ENUM	E33	O	OV _{DD}	—
PCI_GNT[3:4]	F31, F33	O	OV _{DD}	—
M66EN	A19	I	OV _{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	D5, A3, C3, D3, C4, B3, C2, D4, D2, E5, G2, H6, E4, F3, G4, G3, H1, J2, L6, M6, H2, K6, L2, M4, N2, P4, R2, T4, P6, P3, R1, T2, AB5, AA3, AD6, AE4, AB4, AC2, AD3, AE6, AE3, AG4, AK5, AK4, AE2, AG6, AK3, AK2, AL2, AL1, AM5, AP5, AM2, AN1, AP4, AN5, AJ7, AN7, AM8, AJ9, AP6, AL7, AL9, AN8	I/O	GV _{DD}	—

Table 55. MPC8347EA (TBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
Test				
TEST	D22	I	OV _{DD}	6
TEST_SEL	AL13	I	OV _{DD}	7
PMC				
<u>QUIESCE</u>	A18	O	OV _{DD}	—
System Control				
<u>PORESET</u>	C18	I	OV _{DD}	—
<u>HRESET</u>	B18	I/O	OV _{DD}	1
<u>SRESET</u>	D18	I/O	OV _{DD}	2
Thermal Management				
THERM0	K32	I	—	9
Power and Ground Signals				
AV _{DD1}	L31	Power for e300 PLL (1.2 V) nominal, 1.3 V for 667 MHz)	AV _{DD1}	—
AV _{DD2}	AP12	Power for system PLL (1.2 V) nominal, 1.3 V for 667 MHz)	AV _{DD2}	—
AV _{DD3}	AE1	Power for DDR DLL (1.2 V) nominal, 1.3 V for 667 MHz)	—	—
AV _{DD4}	AJ13	Power for LBIU DLL (1.2 V) nominal, 1.3 V for 667 MHz)	AV _{DD4}	—
GND	A1, A34, C1, C7, C10, C11, C15, C23, C25, C28, D1, D8, D20, D30, E7, E13, E15, E17, E18, E21, E23, E25, E32, F6, F19, F27, F30, F34, G31, H5, J4, J34, K30, L5, M2, M5, M30, M33, N3, N5, P30, R5, R32, T5, T30, U6, U29, U33, V2, V5, V30, W6, W30, Y30, AA2, AA30, AB2, AB6, AB30, AC3, AC6, AD31, AE5, AF2, AF5, AF31, AG30, AG31, AH4, AJ3, AJ19, AJ22, AK7, AK13, AK14, AK16, AK18, AK20, AK25, AK28, AL3, AL5, AL10, AL12, AL22, AL27, AM1, AM6, AM7, AN12, AN17, AN34, AP1, AP8, AP34	—	—	—

Table 56. MPC8347EA (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1_TRDY	A13	I/O	OV _{DD}	5
PCI1_IRDY	E13	I/O	OV _{DD}	5
PCI1_STOP	C13	I/O	OV _{DD}	5
PCI1_DEVSEL	B13	I/O	OV _{DD}	5
PCI1_IDSEL	C17	I	OV _{DD}	—
PCI1_SERR	C12	I/O	OV _{DD}	5
PCI1_PERR	B12	I/O	OV _{DD}	5
PCI1_REQ[0]	A21	I/O	OV _{DD}	
PCI1_REQ[1]/CPCI1_HS_ES	C19	I	OV _{DD}	—
PCI1_REQ[2:4]	C18, A19, E20	I	OV _{DD}	—
PCI1_GNT0	B20	I/O	OV _{DD}	—
PCI1_GNT1/CPCI1_HS_LED	C20	O	OV _{DD}	—
PCI1_GNT2/CPCI1_HS_ENUM	B19	O	OV _{DD}	—
PCI1_GNT[3:4]	A20, E18	O	OV _{DD}	—
M66EN	L26	I	OV _{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	AC25, AD27, AD25, AH27, AE28, AD26, AD24, AF27, AF25, AF28, AH24, AG26, AE25, AG25, AH26, AH25, AG22, AH22, AE21, AD19, AE22, AF23, AE19, AG20, AG19, AD17, AE16, AF16, AF18, AG18, AH17, AH16, AG9, AD12, AG7, AE8, AD11, AH9, AH8, AF6, AF8, AE6, AF1, AE4, AG8, AH3, AG3, AG4, AH2, AD7, AB4, AB3, AG1, AD5, AC2, AC1, AC4, AA3, Y4, AA4, AB1, AB2, Y5, Y3	I/O	GV _{DD}	—
MECC[0:4]/MSRCID[0:4]	AG13, AE14, AH12, AH10, AE15	I/O	GV _{DD}	—
MECC[5]/MDVAL	AH14	I/O	GV _{DD}	—
MECC[6:7]	AE13, AH11	I/O	GV _{DD}	—
MDM[0:8]	AG28, AG24, AF20, AG17, AE9, AH5, AD1, AA2, AG12	O	GV _{DD}	—
MDQS[0:8]	AE27, AE26, AE20, AH18, AG10, AF5, AC3, AA1, AH13	I/O	GV _{DD}	—
MBA[0:1]	AF10, AF11	O	GV _{DD}	—
MA[0:14]	AF13, AF15, AG16, AD16, AF17, AH20, AH19, AH21, AD18, AG21, AD13, AF21, AF22, AE1, AA5	O	GV _{DD}	—
MWE	AD10	O	GV _{DD}	—

20.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, use the thermal characterization parameter (Ψ_{JT}) to determine the junction temperature and a measure of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)

T_T = thermocouple temperature on top of package (°C)

Ψ_{JT} = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per the JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

20.2.4 Heat Sinks and Junction-to-Case Thermal Resistance

Some application environments require a heat sink to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)

$R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device-related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

The thermal performance of devices with heat sinks has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, air flow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

Accurate thermal design requires thermal modeling of the application environment using computational fluid dynamics software which can model both the conduction cooling and the convection cooling of the air moving through the application. Simplified thermal models of the packages can be assembled using the junction-to-case and junction-to-board thermal resistances listed in the thermal resistance table. More detailed thermal models can be made available on request.

Heat sink vendors include the following list:

Aavid Thermalloy 80 Commercial St. Concord, NH 03301 Internet: www.aavidthermalloy.com	603-224-9988
Alpha Novatech 473 Sapena Ct. #12 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-567-8082
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277
Millennium Electronics (MEI) Loroco Sites 671 East Brokaw Road San Jose, CA 95112 Internet: www.mei-thermal.com	408-436-8770
Tyco Electronics Chip Coolers™ P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.chipcoolers.com	800-522-2800
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-5102

Interface material vendors include the following:

Chomerics, Inc. 77 Dragon Ct. Woburn, MA 01801 Internet: www.chomerics.com	781-935-4850
Dow-Corning Corporation Dow-Corning Electronic Materials P.O. Box 994 Midland, MI 48686-0997 Internet: www.dowcorning.com	800-248-2481

However, while $\overline{\text{HRESET}}$ is asserted, these pins are treated as inputs, and the value on these pins is latched when $\overline{\text{PORESET}}$ deasserts. Then the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for the output pins.

21.7 Pull-Up Resistor Requirements

The MPC8347EA requires high resistance pull-up resistors (10 k Ω is recommended) on open-drain pins, including I²C pins, and IPIC interrupt pins.

For more information on required pull-up resistors and the connections required for the JTAG interface, refer to application note AN2931, “PowerQUICC Design Checklist.”

22 Ordering Information

This section presents ordering information for the device discussed in this document, and it shows an example of how the parts are marked.

NOTE

The information in this document is accurate for revision 3.x silicon and later (in other words, for orderable part numbers ending in A or B). For information on revision 1.1 silicon and earlier versions, see the *MPC8347E PowerQUICC II Pro Integrated Host Processor Hardware Specifications* (Document Order No. MPC8347EEC).

22.1 Part Numbers Fully Addressed by This Document

Table 70 shows an analysis of the Freescale part numbering nomenclature for the MPC8347EA. The individual part numbers correspond to a maximum processor core frequency. Each part number also contains a revision code that refers to the die mask revision number. For available frequency configuration

parts including extended temperatures, refer to the device product summary page on our website listed on the back cover of this document or, contact your local Freescale sales office.

Table 70. Part Numbering Nomenclature

MPC	nnnn	e	t	pp	aa	a	r
Product Code	Part Identifier	Encryption Acceleration	Temperature ¹ Range	Package ²	Processor Frequency ³	Platform Frequency	Revision Level
MPC	8347	Blank = Not included E = included	Blank = 0 to 105°C C = -40 to 105°C	ZU = TBGA VV = PB free TBGA ZQ = PBGA VR = PB Free PBGA	e300 core speed AD = 266 AG = 400 AJ = 533 AL = 667	D = 266 F = 333 ⁴	B = 3.1

Notes:

1. For temperature range = C, processor frequency is limited to 400 (PBGA) with a platform frequency of 266 and up to 533 (TBGA) with a platform frequency of 333
2. See [Section 18, "Package and Pin Listings,"](#) for more information on available package types.
3. Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by Part Number Specifications may support other maximum core frequencies.
4. ALF marked parts support DDR1 data rate up to 333 MHz (at 333 MHz CSB as the 'F' marking implies) and DDR2 data rate up to 400 MHz (at 200 MHz CSB). AJF marked parts support DDR1 and DDR2 data rate up to 333 MHz (at a CSB of 333 MHz).

[Table 71](#) shows the SVR settings by device and package type.

Table 71. SVR Settings

Device	Package	SVR (Rev. 3.0)
MPC8347EA	TBGA	8052_0030
MPC8347A	TBGA	8053_0030
MPC8347EA	PBGA	8054_0030
MPC8347A	PBGA	8055_0030

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